## WHAT IS CLAIMED IS:

1. A photoelectric conversion device comprising:

a photoelectric conversion region for accumulating electric charges that correspond to incident light; and

an amplifying filed effect transistor into which a signal charge from the photoelectric conversion region is inputted, wherein:

the photoelectric conversion region is surrounded by a potential barrier region;

a nick region is formed in a part of the potential barrier region; and

one of main electrode regions of the field

15 effect transistor is placed adjacent to the nick
region, the main electrode region having the same
conductivity type as the photoelectric conversion
region.

2. A photoelectric conversion device according to claim 1, wherein the potential barrier region includes at least a selectively oxidized film and a channel stopping layer directly below the selectively oxidized film.

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3. A photoelectric conversion device according to claim 1, wherein the potential barrier region

includes at least a buried isolation region whose conductivity type is opposite to that of the photoelectric conversion region.

- 4. A photoelectric conversion device according to claim 1, wherein the photoelectric conversion region is formed in a low impurity concentration region that is doped with an impurity of the same conductivity type as the photoelectric conversion region in a concentration lower than the impurity concentration of the photoelectric conversion region.
  - 5. A photoelectric conversion device according to claim 4, wherein a buried isolation region whose conductivity type is opposite to the conductivity type of the photoelectric conversion region is formed below the field effect transistor.

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A photoelectric conversion device according
 to claim 5,

wherein the buried isolation region placed below the field effect transistor surrounds a region larger than the photoelectric conversion region, and

wherein the region surrounded by the buried 25 isolation region functions as a photosensitive region.

7. A photoelectric conversion device according

to claim 1, wherein an impurity diffusion region whose conductivity type is opposite to the conductivity type of the photoelectric conversion region is provided in the nick region.

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- 8. A photoelectric conversion device according to claim 5, wherein the buried isolation region is not placed in an area below the one main electrode region of the field effect transistor, at least, a part of the area.
- 9. A photoelectric conversion device according to claim 1,

wherein the potential barrier region includes

15 at least a semiconductor region whose conductivity
type is opposite to the conductivity type of the
photoelectric conversion region, and

wherein a buried region that is doped with an impurity of the same conductivity type as the semiconductor region in a concentration lower than the impurity concentration of the semiconductor region is placed in the nick region.

10. A photoelectric conversion device according
25 to claim 4, wherein the low impurity concentration
region is one of a semiconductor substrate, an
epitaxial layer, and a well.

11. A photoelectric conversion device according to claim 1, wherein the one main electrode region is connected to a fixed electric potential or a similar electric potential.

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- 12. A photoelectric conversion device according to claim 1, wherein a semiconductor region whose conductivity type is opposite to the conductivity type of the photoelectric conversion region is placed below the photoelectric conversion region.
- 13. An image pick-up system, comprising: a photoelectric conversion device according to claim 1;
- an optical system for forming an image in the photoelectric conversion device; and
  - a signal processing circuit for processing a signal outputted from the photoelectric conversion device.

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